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		U.S. PATENT DOCUMENTS					
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
/T.D./	A	2005/0234846	10/20/2005	Davidson et al.			
	B	2005/0235092	10/20/2005	Ballew et al.			
	C	2005/0235055	10/20/2005	Ballew et al.			
	D	2005/0235286	10/20/2005	Davidson			
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	G	2006/0112297	05/25/2006	Davidson			
/T.D./	H	2006/0117208	06/01/2006	Richoux			
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	I	WO 02/084509	10/24/2002	PCT			X
NON-PATENT DOCUMENTS							
		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
/T.D./	J	Translated Japanese Patent Application No. 2003-531412, 4 pages, printed 01/04/2008					Printed 01/04/2008
	K	Translation of an Office Action, Japanese Patent Application No. 2005-117406, received 12/28/2007, 6 pages					Received 12/28/2007
	L	Translation of an Office Action, Japanese Patent Application No. 2005-117403, received 12/28/2007, 4 pages					Received 12/28/2007
	M	Translation of an Office Action, Japanese Patent Application No. 2005-117404, received 12/28/2007, 7 pages					Received 12/28/2007
	N	Kimitaka et al., "Liquid Crystal Display Device," Abstracts of Japan for Publication Number 2005-241804, published 09/08/2005, 2 pages					Published 09/08/2005
	O	Hidenori et al., "Magnetic Disk Drive," Abstracts of Japan for Publication Number 2007-141305, published 06/07/2007, 2 pages					Published 06/07/2007
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EXAMINER /Tonia Dollinger/				DATE CONSIDERED 07/04/2008			
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